SDAS206A - APRIL 1982 - REVISED DECEMBER 1994

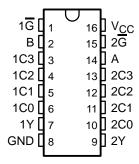
- Permit Multiplexing From n Lines to One Line
- Perform Parallel-to-Serial Conversion
- Strobe (Enable) Line Provided for Cascading (n Lines to n Lines)
- 'ALS253 and SN74AS253A Are 3-State Versions of These Parts
- Package Options Include Plastic Small-Outline (D) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

### description

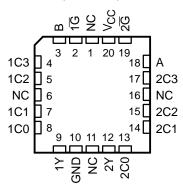
These dual 1-of-4 data selectors/multiplexers contain inverters and drivers to supply full binary decoding data selection to the AND-OR gates. Separate strobe  $(\overline{G})$  inputs are provided for each of the two 4-line sections.

The SN54ALS153 is characterized for operation over the full military temperature range of  $-55^{\circ}$ C to 125°C. The SN74ALS153 and SN74AS153 are characterized for operation from 0°C to 70°C.

### SN54ALS153 . . . J PACKAGE SN74ALS153, SN74AS153 . . . D OR N PACKAGE (TOP VIEW)



# SN54ALS153...FK PACKAGE (TOP VIEW)



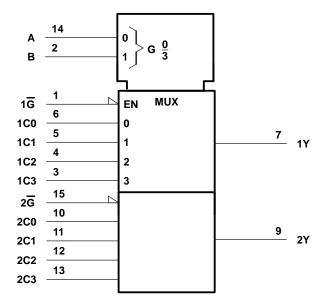
NC - No internal connection

#### **FUNCTION TABLE**

		INP	INPUTS			077075				
SEL	ECT		DA	ΛTA		STROBE G	OUTPUT			
В	Α	C0	C1	C2	C3		•			
Х	Х	Х	Х	Х	Х	Н	L			
L	L	L	Χ	X	Χ	L	L			
L	L	Н	Χ	Χ	Χ	L	Н			
L	Н	Х	L	Χ	Χ	L	L			
L	Н	Х	Н	Χ	Χ	L	Н			
Н	L	Х	Χ	L	Χ	L	L			
Н	L	Х	Χ	Н	Χ	L	Н			
Н	Н	Х	Χ	Χ	L	L	L			
Н	Н	Х	X	X	Н	L	Н			

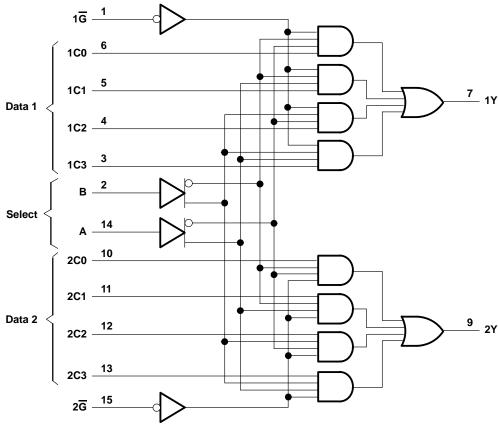
Select inputs A and B are common to both sections.

### logic symbol†



<sup>&</sup>lt;sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for the D, J, and N packages.

### logic diagram (positive logic)



Pin numbers shown are for the D, J, and N packages.



### SN54ALS153, SN74ALS153, SN74AS153 DUAL 1-OF-4 DATA SELECTORS/MULTIPLEXERS

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### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V <sub>CC</sub>	7 \
Input voltage, V <sub>I</sub>	7 \
Operating free-air temperature range, T <sub>A</sub> : SN54ALS153	
SN74ALS153	0°C to 70°0
Storage temperature range	-65°C to 150°€

### recommended operating conditions

		SN	54ALS1	53	SN	74ALS1	53	UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
V <sub>IH</sub>	High-level input voltage	2			2			V
V <sub>IL</sub>	Low-level input voltage			0.7			0.8	V
IOH	High-level output current			-1			-2.6	mA
lOL	Low-level output current			12			24	mA
TA	Operating free-air temperature	-55		125	0		70	°C

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETED	TEST CONDITIONS		SN	54ALS1	53	SN74ALS153			UNIT
PARAMETER			MIN	TYP <sup>‡</sup>	MAX	MIN	TYP <sup>‡</sup>	MAX	UNII
VIK	$V_{CC} = 4.5 V,$	$I_1 = -18 \text{ mA}$			-1.5			-1.5	V
	$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V},$	$I_{OH} = -0.4 \text{ mA}$	V <sub>CC</sub> -2			V <sub>CC</sub> -2	2		
VOH	V <sub>CC</sub> = 4.5 V	$I_{OH} = -1 \text{ mA}$	2.4	3.3					V
	vCC = 4.5 v	$I_{OH} = -2.6 \text{ mA}$				2.4	3.2		
V	V <sub>CC</sub> = 4.5 V	I <sub>OL</sub> = 12 mA		0.25	0.4		0.25	0.4	V
VOL		I <sub>OL</sub> = 24 mA					0.35	0.5	
lį	$V_{CC} = 5.5 \text{ V},$	V <sub>I</sub> = 7 V			0.1			0.1	mA
lН	$V_{CC} = 5.5 \text{ V},$	V <sub>I</sub> = 2.7 V			20			20	μΑ
I <sub>IL</sub>	$V_{CC} = 5.5 V$ ,	V <sub>I</sub> = 0.4 V			-0.1			-0.1	mA
ΙΟ§	V <sub>CC</sub> = 5.5 V,	V <sub>O</sub> = 2.25 V	-20		-112	-30		-112	mA
lcc	V <sub>CC</sub> = 5.5 V,	All inputs at 4.5 V		7.5	14		7.5	14	mA

<sup>‡</sup> All typical values are at  $V_{CC} = 5 \text{ V}$ ,  $T_A = 25^{\circ}\text{C}$ .



<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

<sup>§</sup> The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, IOS.

### SN54ALS153, SN74ALS153, SN74AS153 DUAL 1-OF-4 DATA SELECTORS/MULTIPLEXERS

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### switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	C <sub>L</sub> R <sub>L</sub> T <sub>A</sub>	$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V},$ $C_{L} = 50 \text{ pF},$ $R_{L} = 500 \Omega,$ $T_{A} = \text{MIN to MAX}^{\dagger}$ SN54ALS153 SN74ALS153			UNIT
			MIN	MAX	MIN	MAX	
<sup>t</sup> PLH	A or B	Y	5	29	5	21	
<sup>t</sup> PHL	AUID	T	5	27	5	21	ns
t <sub>PLH</sub>	Data	Y	3	15	3	10	no
<sup>t</sup> PHL	(any C)	I	2	18	4	15	ns
t <sub>PLH</sub>	ĪG	Y	5	27	5	18	nc
t <sub>PHL</sub>	9	ľ	3	22	5	18	ns

T For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

## absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage, V <sub>CC</sub>	7 V
Input voltage, V <sub>I</sub>	7 V
Operating free-air temperature range, T <sub>A</sub> : SN74AS153	0°C to 70°C
Storage temperature range	. −65°C to 150°C

<sup>‡</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

### recommended operating conditions

		SN	174AS15	3	UNIT
		MIN	NOM	MAX	UNIT
Vcc	Supply voltage	4.5	5	5.5	V
VIH	High-level input voltage	2			V
V <sub>IL</sub>	Low-level input voltage			0.8	V
lOH	High-level output current			-15	mA
loL	Low-level output current			48	mA
TA	Operating free-air temperature	0		70	°C

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# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CONF	NTIONE	SN	174AS15	i3	UNIT
FARAIVIETER		TEST CONL	TEST CONDITIONS		TYP†	MAX	UNII
٧ıĸ		V <sub>CC</sub> = 4.5 V,	I <sub>I</sub> = -18 mA			-1.2	V
V		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V},$	$I_{OH} = -2 \text{ mA}$	V <sub>CC</sub> -2			V
VOH		V <sub>CC</sub> = 4.5 V,	I <sub>OH</sub> = -15 mA	2.4	3.2		V
VOL		$V_{CC} = 4.5 V,$	I <sub>OL</sub> = 48 mA		0.35	0.5	V
1.	A, B	V 55V	V. 7V			MAX -1.2	A
¹	All others	$V_{CC} = 5.5 V$	V <sub>I</sub> = 7 V				mA
1	A, B	V 55V	V. 07V.			40	A
ΊΗ	All others	$V_{CC} = 5.5 V$ ,	V <sub>I</sub> =27.Y′ v			20	μΑ
	A, B	V 55V	V 04M.			-1	A
ΊL	All others	$V_{CC} = 5.5 V$ ,	۷۱ = <b>℃</b> :۲4′ ۷			-0.5	mA
lo <sup>‡</sup>		V <sub>CC</sub> = 5.5 V,	V <sub>O</sub> = 2.25 V	-30		-112	mA
ІССН		V <sub>CC</sub> = 5.5 V			16	26	mA
ICCL		V <sub>CC</sub> = 5.5 V			21	33	mA

<sup>†</sup> All typical values are at  $V_{CC} = 5 \text{ V}$ ,  $T_A = 25^{\circ}\text{C}$ .

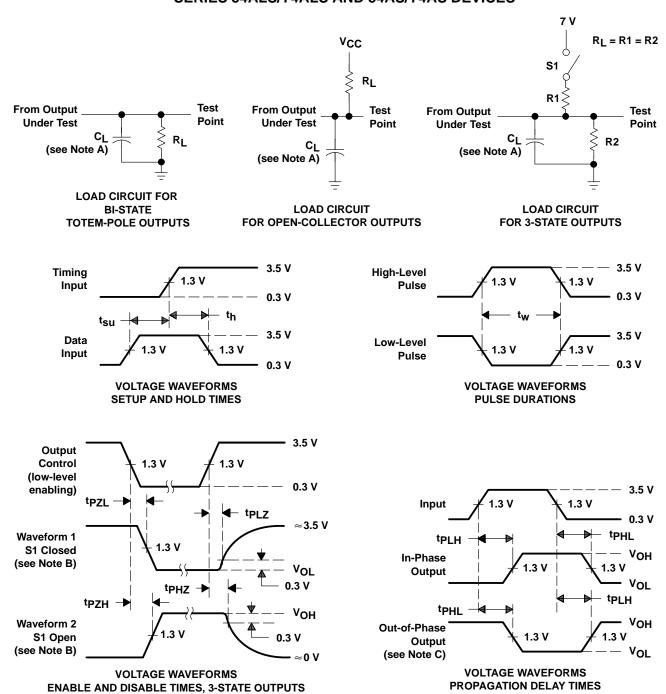
### switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	R <sub>L</sub> = 500 T <sub>A</sub> = MIN	i V to 5.5 V, F, Ω, to MAX§	UNIT
			MIN	MAX	
<sup>t</sup> PLH	A or B	Y	3	12.5	ns
<sup>t</sup> PHL	A 01 B	1	3	11	115
t <sub>PLH</sub>	Data		2	7	ns
<sup>t</sup> PHL	(any C)	1	2	8	115
<sup>t</sup> PLH	G	<b>Y</b>	3	11.5	ns
t <sub>PHL</sub>	G	'	10	9	115

<sup>§</sup> For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

<sup>‡</sup> The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, IOS.

### PARAMETER MEASUREMENT INFORMATION SERIES 54ALS/74ALS AND 54AS/74AS DEVICES



- NOTES: A. C<sub>L</sub> includes probe and jig capacitance.
  - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
  - C. When measuring propagation delay items of 3-state outputs, switch S1 is open.
  - D. All input pulses have the following characteristics: PRR  $\leq$  1 MHz,  $t_f = t_f = 2$  ns, duty cycle = 50%.
  - E. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuits and Voltage Waveforms



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